

ABSTRACT

A pusher 30 is constituted by a pusher main body 31, 33 which is capable of direct contact with an electronic component 2 to be tested, a heat absorbing and radiating body 35 provided on the pusher main body 31, 33, a heater 311 provided on the pusher main body 31, 33 to enable direct or indirect contact with the electronic component 2 to be tested, and a thermal insulating material 312 provided between the pusher main body 31, 33 and the heater 311.

According to such a pusher 30, temperature control of an electronic component can be performed such that the electronic component nears a target set temperature for testing.